

Silicon P-Channel Power MOSFET

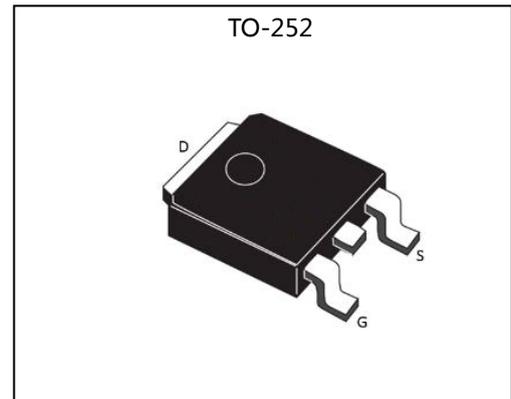
General Description :

The HMR65P06 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-252, which accords with the RoHS standard.

V_{DSS}	-60	V
I_D	-65	A
P_D	130	W
$R_{DS(ON)}$	13	m Ω

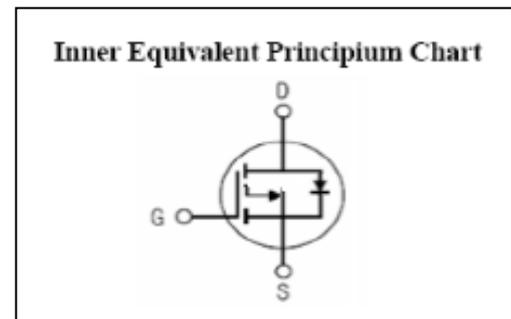
Features :

- Fast Switching
- Low Gate Charge and Rds(on)
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test



Applications :

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Absolute ($T_c=25^\circ\text{C}$ unless otherwise specified) :

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	-60	V
I_D	Continuous Drain Current	-65	A
	Continuous Drain Current $T_C=100^\circ\text{C}$	-45	A
I_{DM}^{a1}	Pulsed Drain Current	-260	A
V_{GS}	Gate-to-Source Voltage	± 20	V
dv/dt^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	130	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	175 , -55 to 175	$^\circ\text{C}$
T_L	Maximum Temperature for Soldering	300	$^\circ\text{C}$

Electrical Characteristics (Tc=25°C unless otherwise specified) :

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =-250μA	-60	--	--	V
ΔBV _{DSS} /ΔT _J	Bvdss Temperature Coefficient	I _D =-250uA, Reference 25°C	--	0.02	--	V/°C
I _{DSS}	Drain to Source Leakage Current	V _{DS} =-60, V _{GS} = 0V, T _a =25°C	--	--	-1	μA
		V _{DS} =-48V, V _{GS} = 0V, T _a =125°C	--	--	-250	
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} = +20V	--	--	1	μA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} = -20V	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =-10V, I _D =-20.0A	--	13	23	mΩ
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250μA	-1.0	--	-3.0	V
Pulse width tp ≤ 380μs, δ ≤ 2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} =-10V, I _D =-20A	--	25	--	S
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-25V f=1.0MHz	--	5700	--	pF
C _{oss}	Output Capacitance		--	470	--	
C _{rss}	Reverse Transfer Capacitance		--	220	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	R _L =-1.5Ω, V _{DD} =-30V V _{GS} =-10V, R _G =3Ω	--	20	--	ns
t _r	Rise Time		--	20	--	
t _{d(OFF)}	Turn-Off Delay Time		--	50	--	
t _f	Fall Time		--	30	--	
Q _g	Total Gate Charge	I _D =-30.0A, V _{DD} =-20V V _{GS} =-10V	--	70	--	nC
Q _{gs}	Gate to Source Charge		--	16	--	
Q _{gd}	Gate to Drain ("Miller") Charge		--	17	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	-65	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	-120	A
V_{SD}	Diode Forward Voltage	$I_S = -30A, V_{GS} = 0V$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$I_S = -20A, T_j = 25^\circ C$	--	50	--	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s, V_{GS} = 0V$	--	70	--	nC
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Symbol	Parameter	Typ.	Units
$R_{\theta JA}$	Junction-to-Ambient	0.97	$^\circ C/W$

^{a1} : Repetitive rating; pulse width limited by maximum junction temperature

^{a3} : $I_{SD} = -30A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_j = 25^\circ C$

Typical Electrical and Thermal Characteristics

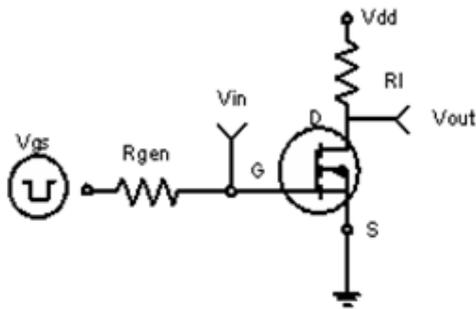


Figure 1: Switching Test Circuit

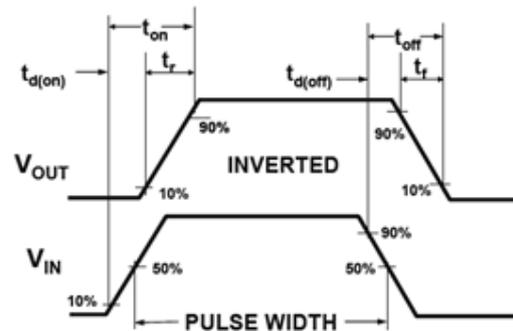


Figure 2: Switching Waveforms

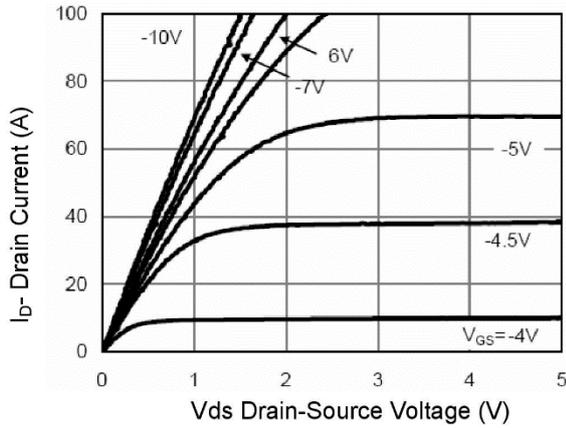


Figure 1 Output Characteristics

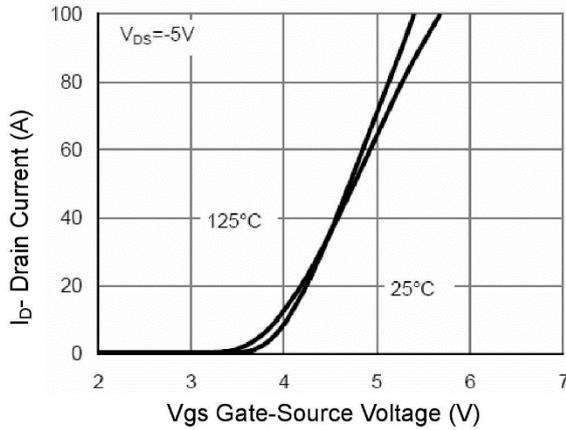


Figure 2 Transfer Characteristics

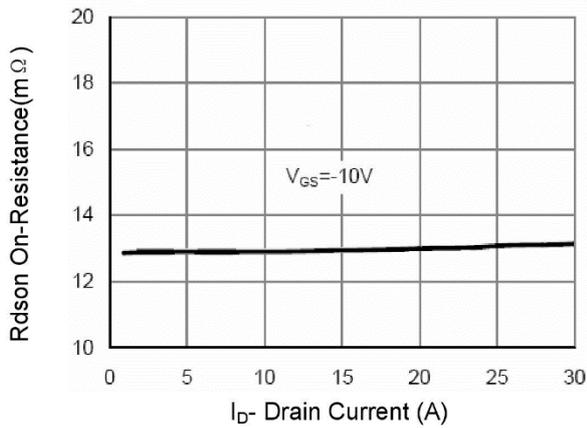


Figure 3 Rdson- Drain Current

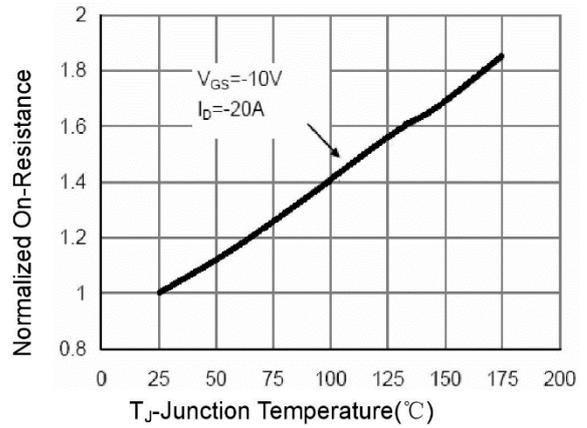


Figure 4 Rdson-Junction Temperature

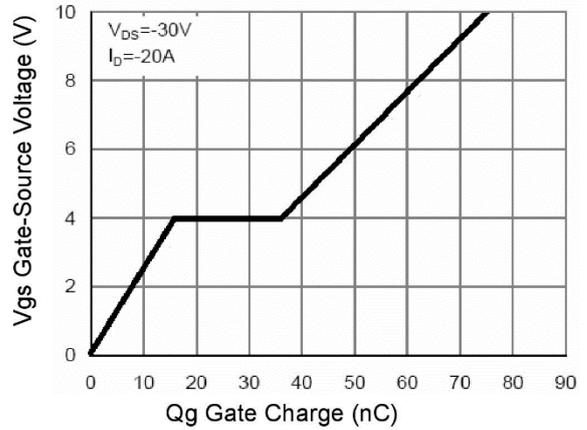


Figure 5 Gate Charge

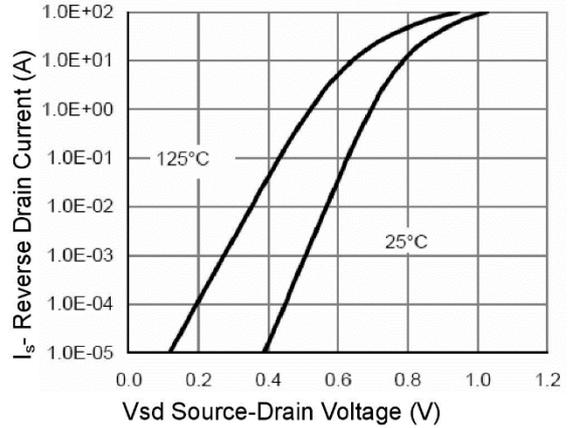


Figure 6 Source- Drain Diode Forward

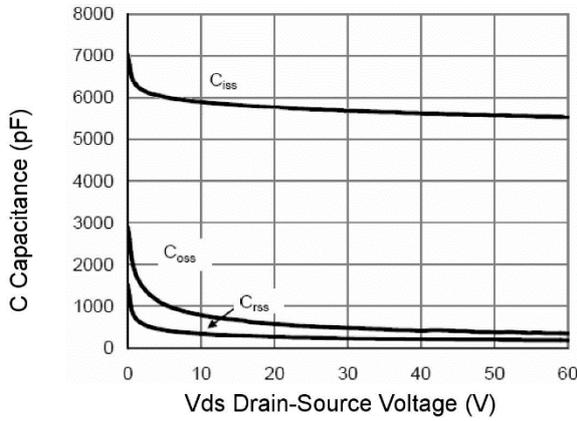


Figure 7 Capacitance vs Vds

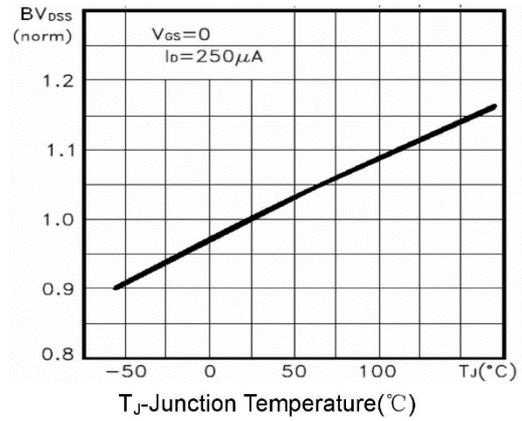


Figure 9 BV_{DSS} vs Junction Temperature

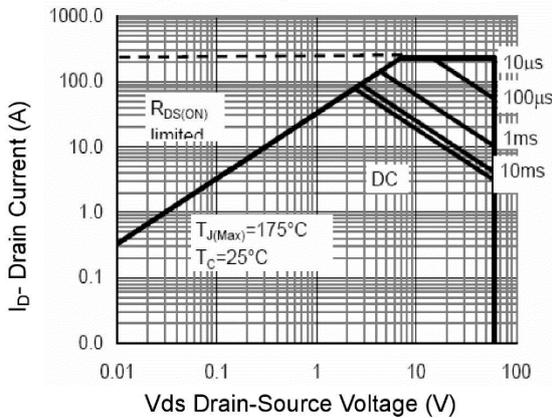


Figure 8 Safe Operation Area

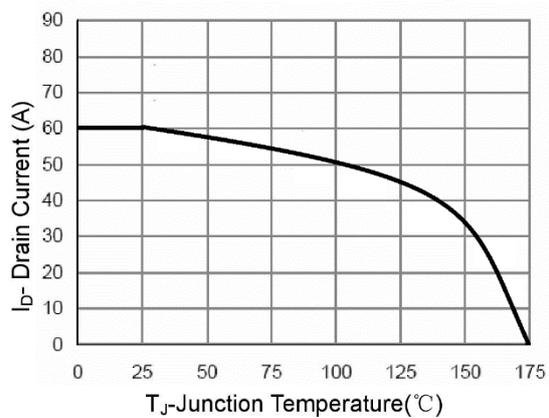


Figure 10 I_D Current Derating vs Junction Temperature

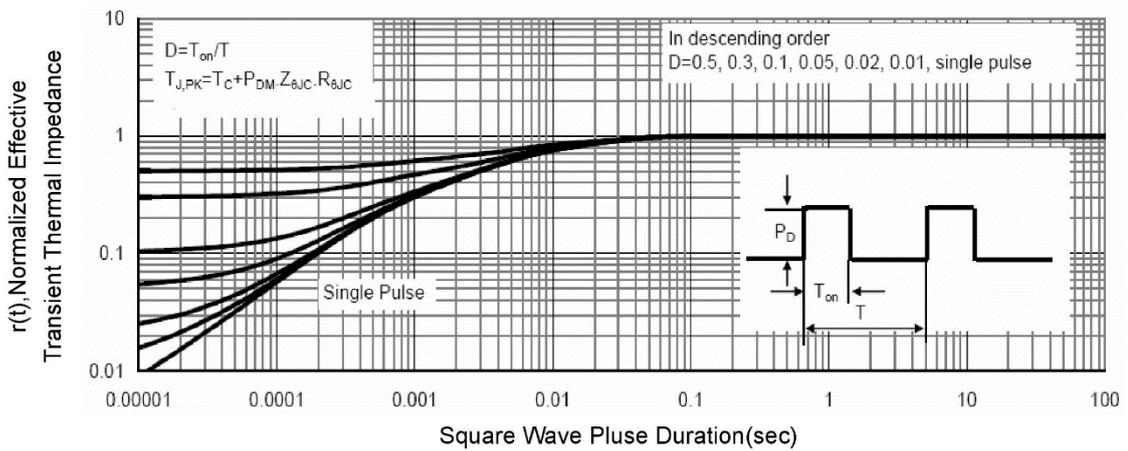


Figure 11 Normalized Maximum Transient Thermal Impedance